



SAR TEST REPORT

No. 24T04Z100845-003

For

TCL Communication Ltd.

TWS Headphone

Model name: TW421

with

Hardware Version: V1.1

Software Version: V1.7.0

FCC ID: 2ACCJB220

Issued Date: 2024-5-9

Note:

The test results in this test report relate only to the devices specified in this report. This report shall not be reproduced except in full without the written approval of CTTL.

Test Laboratory:

CTTL, Telecommunication Technology Labs, CAICT

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No. 24T04Z100845-003

REPORT HISTORY

Report Number	Revision	Issue Date	Description
24T04Z100845-003	Rev.0	2024-5-9	Initial creation of test report

TABLE OF CONTENT

1 TEST LABORATORY	4
1.1 INTRODUCTION & ACCREDITATION	4
1.2 TESTING LOCATION	4
1.3 TESTING ENVIRONMENT.....	5
1.4 PROJECT DATA	5
1.5 SIGNATURE.....	5
2 CLIENT INFORMATION.....	6
2.1 APPLICANT INFORMATION	6
2.2 MANUFACTURER INFORMATION	6
3 EQUIPMENT UNDER TEST (EUT) AND ANCILLARY EQUIPMENT (AE)	7
3.1 ABOUT EUT.....	7
3.2 INTERNAL IDENTIFICATION OF EUT USED DURING THE TEST	7
3.3 INTERNAL IDENTIFICATION OF AE USED DURING THE TEST	7
4 TEST METHODOLOGY	8
4.1 APPLICABLE LIMIT REGULATIONS.....	8
4.2 APPLICABLE MEASUREMENT STANDARDS	8
5 SPECIFIC ABSORPTION RATE (SAR).....	9
5.1 INTRODUCTION.....	9
5.2 SAR DEFINITION.....	9
6 MEASUREMENT PROCEDURES	10
6.1 TESTS TO BE PERFORMED	10
6.2 GENERAL MEASUREMENT PROCEDURE.....	12
6.3 BLUETOOTH & WI-FI MEASUREMENT PROCEDURES FOR SAR	13
6.4 POWER DRIFT.....	13
7 CONDUCTED OUTPUT POWER	14
7.1 BT MEASUREMENT RESULT.....	14
8 SAR TEST EXCLUSION CONSIDERATIONS.....	14
8.1 TRANSMIT ANTENNA SEPARATION DISTANCES.....	14
8.2 STANDALONE SAR TEST EXCLUSION CONSIDERATIONS	14
ANNEX ACCREDITATION CERTIFICATE	15



No. 24T04Z100845-003

1 Test Laboratory

1.1 Introduction & Accreditation

Telecommunication Technology Labs, CAICT is an ISO/IEC 17025:2017 accredited test laboratory under American Association for Laboratory Accreditation (A2LA) with lab code 7049.01, and is also an FCC accredited test laboratory (CN1349), and ISED accredited test laboratory (CAB identifier:CN0066). The detail accreditation scope can be found on A2LA website.

1.2 Testing Location

CompanyName:	CTTL
Address:	No. 52, Huayuan North Road, Haidian District, Beijing, P. R. China 100191.

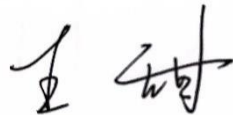
1.3 Testing Environment

Temperature:	18°C~25°C,
Relative humidity:	30%~ 70%
Ground system resistance:	< 0.5 Ω
Ambient noise is checked and found very low and in compliance with requirement of standards. Reflection of surrounding objects is minimized and in compliance with requirement of standards.	

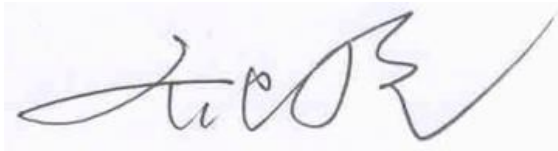
1.4 Project Data

Project Leader:	Qi Dianyuan
Test Engineer:	Wang Tian
Testing Start Date:	\
Testing End Date:	\

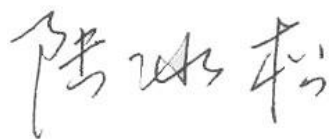
1.5 Signature



Wang Tian
(Prepared this test report)



Qi Dianyuan
(Reviewed this test report)



Lu Bingsong
Deputy Director of the laboratory
(Approved this test report)



2 Client Information

2.1 Applicant Information

Company Name:	TCL Communication Ltd.
Address/Post:	5/F, Building 22E, 22 Science Park East Avenue, Hong Kong Science Park, Shatin, NT, Hong Kong
Contact Person:	Annie Jiang
Contact Email:	nianxiang.jiang@tcl.com
Telephone:	+86 755 3661 1621
Fax	+86 755 3661 2000-81722

2.2 Manufacturer Information

Company Name:	TCL Communication Ltd.
Address/Post:	5/F, Building 22E, 22 Science Park East Avenue, Hong Kong Science Park, Shatin, NT, Hong Kong
Contact Person:	Annie Jiang
Contact Email:	nianxiang.jiang@tcl.com
Telephone:	+86 755 3661 1621
Fax	+86 755 3661 2000-81722

3 Equipment Under Test (EUT) and Ancillary Equipment (AE)

3.1 About EUT

Description:	TWS Headphone
Model name:	TW421
Operating mode(s):	Bluetooth
Tested Tx Frequency:	2400 – 2483.5 MHz (Bluetooth)
Test device Production information:	Production unit
Device type:	Portable device
Antenna type:	Integrated antenna
Hotspot mode:	Not Support

3.2 Internal Identification of EUT used during the test

EUT ID*	SN/IMEI	HW Version	SW Version
EUT1	\	\	\

*EUT ID: is used to identify the test sample in the lab internally.

3.3 Internal Identification of AE used during the test

AE ID*	Description	Model	SN	Manufacturer
AE1	Battery	1154PF2	/	VDL
AE2	Battery	542627PF4	/	VDL

*AE ID: is used to identify the test sample in the lab internally.

4 TEST METHODOLOGY

4.1 Applicable Limit Regulations

ANSI C95.1–1992: IEEE Standard for Safety Levels with Respect to Human Exposure to Radio Frequency Electromagnetic Fields, 3 kHz to 300 GHz.

It specifies the maximum exposure limit of **1.6 W/kg** as averaged over any 1 gram of tissue for portable devices being used within 20 cm of the user in the uncontrolled environment.

4.2 Applicable Measurement Standards

IEEE 1528–2013: Recommended Practice for Determining the Peak Spatial-Average Specific Absorption Rate (SAR) in the Human Head from Wireless Communications Devices: Measurement Techniques.

KDB447498 D01: General RF Exposure Guidance v06: Mobile and Portable Devices RF Exposure Procedures and Equipment Authorization Policies.

KDB865664 D01 SAR measurement 100 MHz to 6 GHz v01r04: SAR Measurement Requirements for 100 MHz to 6 GHz.

KDB865664 D02 RF Exposure Reporting v01r02: RF Exposure Compliance Reporting and Documentation Considerations

5 Specific Absorption Rate (SAR)

5.1 Introduction

SAR is related to the rate at which energy is absorbed per unit mass in an object exposed to a radio field. The SAR distribution in a biological body is complicated and is usually carried out by experimental techniques or numerical modeling. The standard recommends limits for two tiers of groups, occupational/controlled and general population/uncontrolled, based on a person's awareness and ability to exercise control over his or her exposure. In general, occupational/controlled exposure limits are higher than the limits for general population/uncontrolled.

5.2 SAR Definition

The SAR definition is the time derivative (rate) of the incremental energy (dW) absorbed by (dissipated in) an incremental mass (dm) contained in a volume element (dv) of a given density (ρ). The equation description is as below:

$$SAR = \frac{d}{dt} \left(\frac{dW}{dm} \right) = \frac{d}{dt} \left(\frac{dW}{\rho dv} \right)$$

SAR is expressed in units of Watts per kilogram (W/kg)

SAR measurement can be either related to the temperature elevation in tissue by

$$SAR = c \left(\frac{\delta T}{\delta t} \right)$$

Where: C is the specific heat capacity, δT is the temperature rise and δt is the exposure duration, or related to the electrical field in the tissue by

$$SAR = \frac{\sigma |E|^2}{\rho}$$

Where: σ is the conductivity of the tissue, ρ is the mass density of tissue and E is the RMS electrical field strength.

However for evaluating SAR of low power transmitter, electrical field measurement is typically applied.

6 Measurement Procedures

6.1 Tests to be performed

In order to determine the highest value of the peak spatial-average SAR of a handset, all device positions, configurations and operational modes shall be tested for each frequency band according to steps 1 to 3 below. A flowchart of the test process is shown in picture 6.1.

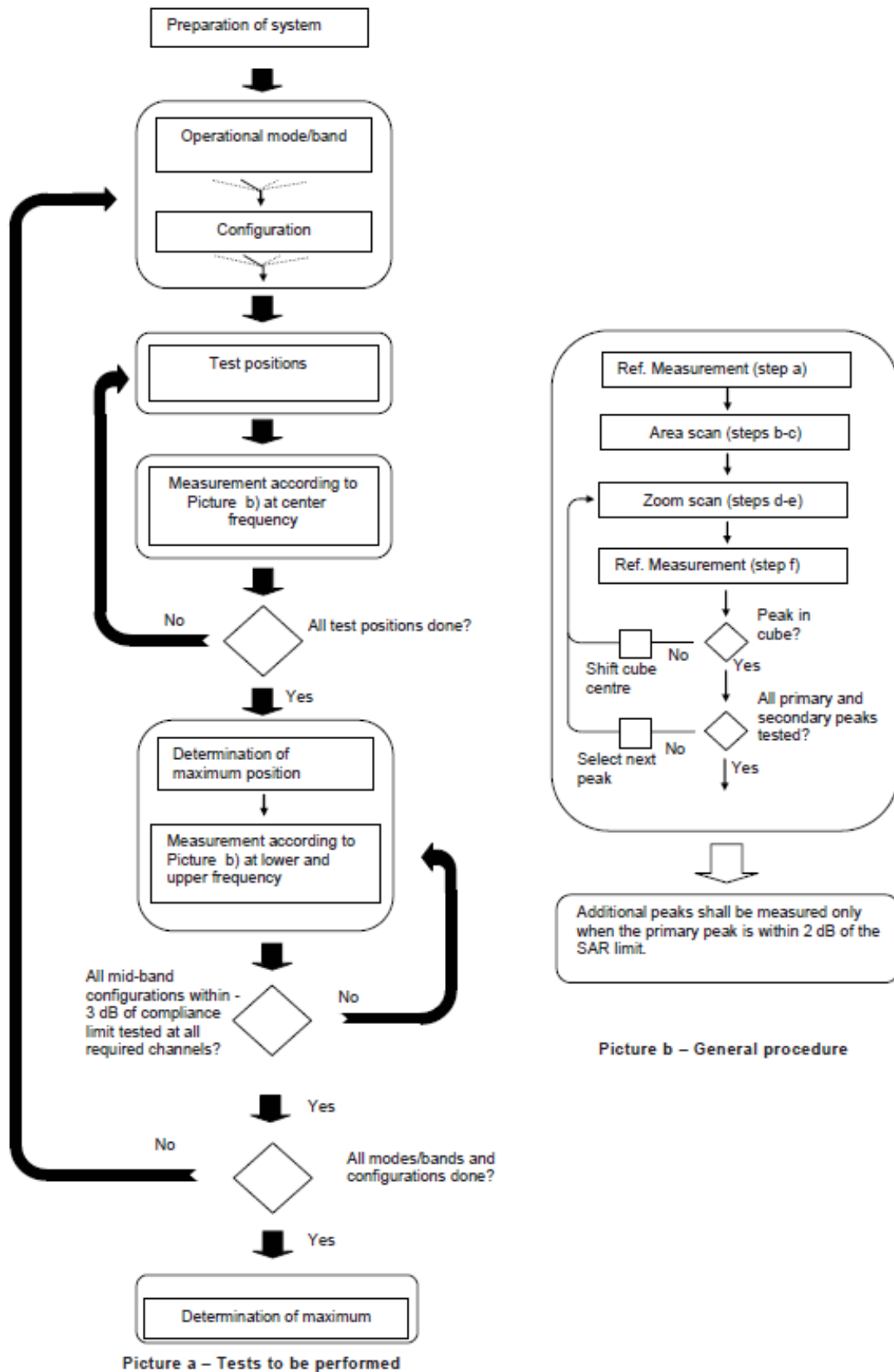
Step 1: The tests described in 6.2 shall be performed at the channel that is closest to the centre of the transmit frequency band (f_c) for:

- a) all device positions (cheek and tilt, for both left and right sides of the SAM phantom, as described in annex D),
- b) all configurations for each device position in a), e.g., antenna extended and retracted, and
- c) all operational modes, e.g., analogue and digital, for each device position in a) and configuration in b) in each frequency band.

If more than three frequencies need to be tested according to 11.1 (i.e., $N_c > 3$), then all frequencies, configurations and modes shall be tested for all of the above test conditions.

Step 2: For the condition providing highest peak spatial-average SAR determined in Step 1, perform all tests described in 6.2 at all other test frequencies, i.e., lowest and highest frequencies. In addition, for all other conditions (device position, configuration and operational mode) where the peak spatial-average SAR value determined in Step 1 is within 3 dB of the applicable SAR limit, it is recommended that all other test frequencies shall be tested as well.

Step 3: Examine all data to determine the highest value of the peak spatial-average SAR found in Steps 1 to 2.



Picture 6.1 Block diagram of the tests to be performed

6.2 General Measurement Procedure

The area and zoom scan resolutions specified in the table below must be applied to the SAR measurements and fully documented in SAR reports to qualify for TCB approval. Probe boundary effect error compensation is required for measurements with the probe tip closer than half a probe tip diameter to the phantom surface. Both the probe tip diameter and sensor offset distance must satisfy measurement protocols; to ensure probe boundary effect errors are minimized and the higher fields closest to the phantom surface can be correctly measured and extrapolated to the phantom surface for computing 1-g SAR. Tolerances of the post-processing algorithms must be verified by the test laboratory for the scan resolutions used in the SAR measurements, according to the reference distribution functions specified in IEEE Std 1528-2003. The results should be documented as part of the system validation records and may be requested to support test results when all the measurement parameters in the following table are not satisfied.

		≤ 3 GHz	> 3 GHz	
Maximum distance from closest measurement point (geometric center of probe sensors) to phantom surface		5 ± 1 mm	$\frac{1}{2} \cdot \delta \cdot \ln(2) \pm 0.5$ mm	
Maximum probe angle from probe axis to phantom surface normal at the measurement location		$30^\circ \pm 1^\circ$	$20^\circ \pm 1^\circ$	
Maximum area scan spatial resolution: Δx_{Area} , Δy_{Area}		≤ 2 GHz: ≤ 15 mm 2 – 3 GHz: ≤ 12 mm	3 – 4 GHz: ≤ 12 mm 4 – 6 GHz: ≤ 10 mm	
		When the x or y dimension of the test device, in the measurement plane orientation, is smaller than the above, the measurement resolution must be \leq the corresponding x or y dimension of the test device with at least one measurement point on the test device.		
Maximum zoom scan spatial resolution: Δx_{Zoom} , Δy_{Zoom}		≤ 2 GHz: ≤ 8 mm 2 – 3 GHz: ≤ 5 mm*	3 – 4 GHz: ≤ 5 mm* 4 – 6 GHz: ≤ 4 mm*	
Maximum zoom scan spatial resolution, normal to phantom surface	uniform grid: $\Delta z_{Zoom}(n)$	≤ 5 mm	3 – 4 GHz: ≤ 4 mm 4 – 5 GHz: ≤ 3 mm 5 – 6 GHz: ≤ 2 mm	
	graded grid	$\Delta z_{Zoom}(1)$: between 1 st two points closest to phantom surface	≤ 4 mm	3 – 4 GHz: ≤ 3 mm 4 – 5 GHz: ≤ 2.5 mm 5 – 6 GHz: ≤ 2 mm
		$\Delta z_{Zoom}(n>1)$: between subsequent points	$\leq 1.5 \cdot \Delta z_{Zoom}(n-1)$	
Minimum zoom scan volume	x, y, z	≥ 30 mm	3 – 4 GHz: ≥ 28 mm 4 – 5 GHz: ≥ 25 mm 5 – 6 GHz: ≥ 22 mm	
Note: δ is the penetration depth of a plane-wave at normal incidence to the tissue medium; see draft standard IEEE P1528-2011 for details. * When zoom scan is required and the <i>reported</i> SAR from the area scan based 1-g SAR estimation procedures of KDB 447498 is ≤ 1.4 W/kg, ≤ 8 mm, ≤ 7 mm and ≤ 5 mm zoom scan resolution may be applied, respectively, for 2 GHz to 3 GHz, 3 GHz to 4 GHz and 4 GHz to 6 GHz.				

6.3 Bluetooth & Wi-Fi Measurement Procedures for SAR

Normal network operating configurations are not suitable for measuring the SAR of 802.11 transmitters in general. Unpredictable fluctuations in network traffic and antenna diversity conditions can introduce undesirable variations in SAR results. The SAR for these devices should be measured using chipset based test mode software to ensure that the results are consistent and reliable.

Chipset based test mode software is hardware dependent and generally varies among manufacturers. The device operating parameters established in a test mode for SAR measurements must be identical to those programmed in production units, including output power levels, amplifier gain settings and other RF performance tuning parameters. The test frequencies should correspond to actual channel frequencies defined for domestic use. SAR for devices with switched diversity should be measured with only one antenna transmitting at a time during each SAR measurement, according to a fixed modulation and data rate. The same data pattern should be used for all measurements.

6.4 Power Drift

To control the output power stability during the SAR test, DASY5 system calculates the power drift by measuring the E-field at the same location at the beginning and at the end of the measurement for each test position. This ensures that the power drift during one measurement is within 5%.

7 Conducted Output Power

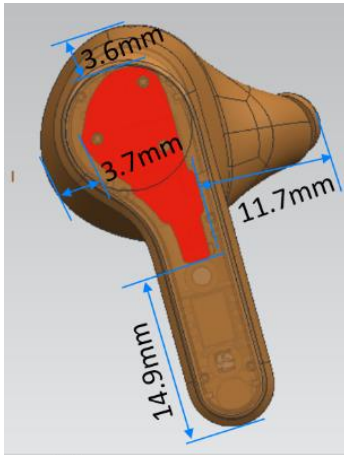
7.1 BT Measurement result

Right ear- GFSK		
Channel 0	Channel 39	Channel 78
6.39	6.27	5.53

The maximum tune up of BT antenna is 8dBm.

8 SAR Test Exclusion Considerations

8.1 Transmit Antenna Separation Distances



8.2 Standalone SAR Test Exclusion Considerations

Standalone 1-g head or body SAR evaluation by measurement or numerical simulation is not required when the corresponding SAR Exclusion Threshold condition, listed below, is satisfied. The 1-g SAR test exclusion threshold for 100 MHz to 6 GHz at test separation distances ≤ 50 mm are determined by:

$$\left[\frac{\text{[(max. power of channel, including tune-up tolerance, mW)]}{\text{[(min. test separation distance, mm)]}} \cdot \sqrt{f(\text{GHz})} \right] \leq 3.0 \text{ for 1-g SAR, where}$$

- $f(\text{GHz})$ is the RF channel transmit frequency in GHz
- Power and distance are rounded to the nearest mW and mm before calculation
- The result is rounded to one decimal place for comparison

Table 8.1: Standalone SAR test exclusion considerations

Band/Mode	F(GHz)	Position	SAR test exclusion threshold(mW)	RF output power		SAR test exclusion
				dBm	mW	
Bluetooth	2.441	Head	9.60	8	6.31	YES

ANNEX Accreditation Certificate**Accredited Laboratory**

A2LA has accredited

TELECOMMUNICATION TECHNOLOGY LABS, CAICT*Beijing, People's Republic of China*

for technical competence in the field of

Electrical Testing

This laboratory is accredited in accordance with the recognized International Standard ISO/IEC 17025:2017 *General requirements for the competence of testing and calibration laboratories*. This accreditation demonstrates technical competence for a defined scope and the operation of a laboratory quality management system (refer to joint ISO-ILAC-IAF Communiqué dated April 2017).

Presented this 26th day of June 2023.

Mr. Trace McInturff, Vice President, Accreditation Services
For the Accreditation Council
Certificate Number 7049.01
Valid to July 31, 2024

For the tests to which this accreditation applies, please refer to the laboratory's Electrical Scope of Accreditation.